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Shah, Y.C.; Chapman, R.; Mahani, R.B.;
Pattern Analysis and Machine Intelligence, IEEE Transactions on , Volume: 11 , Issue: 7 , July 1989
Pages:768 - 773

[Abstract]   [PDF Full-Text (464 KB)]   **IEEE JNL**

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2 **Electronic endoscope system for shape measurement**
Hasegawa, K.; Noda, K.; Sato, Y.;
Pattern Recognition, 2002. Proceedings. 16th International Conference on , Volume: 1 , 11-15 Aug. 2002
Pages:792 - 795 vol.1

[Abstract]   [PDF Full-Text (346 KB)]   **IEEE CNF**

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3 **Spatial color component matching of images**
Jianying Hu; Hadjidemetriou, E.;
Pattern Recognition, 2002. Proceedings. 16th International Conference on , Volume: 3 , 11-15 Aug. 2002
Pages:948 - 951 vol.3

[Abstract]   [PDF Full-Text (387 KB)]   **IEEE CNF**

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4 **Electronic endoscope system for shape measurement**
Hasegawa, K.; Noda, K.; Sato, Y.;

Pattern Recognition, 2002. Proceedings. 16th International Conference on , Volume: 2 , 11-15 Aug. 2002
Pages:761 - 764 vol.2

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